1. Record Nr. UNINA9910413060403321

Autore	Amirante, Domenico
Titolo	Lo Stato multiculturale : contributo alla teoria dello Stato dalla prospettiva dell'Unione indiana / Domenico Amirante
Pubbl/distr/stampa	Bologna, : Bononia University Press, 2014
ISBN	978-88-6923-009-7
Descrizione fisica	174 p. ; 24 cm
Collana	Ricerche di diritto pubblico comparato
Disciplina	342.54
Locazione	FSPBC
Collocazione	I C 400
Lingua di pubblicazione	Italiano
Formato	Materiale a stampa
Livello bibliografico	Monografia

2. Record Nr. UNINA9910146242703321

Autore	Bubert Henning
Titolo	Surface and Thin Film Analysis : A Compendium of Principles, Instrumentation and Applications
Pubbl/distr/stampa	Hoboken, : Wiley, 2011
ISBN	1-280-55760-5 9786610557608 3-527-60016-7
Edizione	[2nd ed.]
Descrizione fisica	1 online resource (559 p.)
Altri autori (Persone)	JenettHolger
Disciplina	530.4275 541.33
Soggetti	Thin films - Analysis - Surfaces Electron spectroscopy Spectrum analysis Electronic books.
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di contenuto	Surface and Thin Film Analysis: A Compendium of Principles, Instrumentation, and Applications; Contents; Preface to the First Edition; Preface to the Second Edition; List of Contributors; 1: Introduction; Part One: Electron Detection; 2: X-Ray Photoelectron Spectroscopy (XPS); 2.1 Principles; 2.2 Instrumentation; 2.2.1 Vacuum Requirements; 2.2.2 X-Ray Sources; 2.2.3 Synchrotron Radiation; 2.2.4 Electron Energy Analyzers; 2.2.5 Spatial Resolution; 2.3 Spectral Information and Chemical Shifts; 2.4 Quantification, Depth Profiling, and Imaging; 2.4.1 Quantification; 2.4.2 Depth Profiling 2.4.3 Imaging2.5 The A uger Parameter; 2.6 Applications; 2.6.1 Catalysis; 2.6.2 Polymers; 2.6.3 Corrosion and Passivation; 2.6.4 Adhesion; 2.6.5 Superconductors; 2.6.6 Semiconductors; 2.7 Ultraviolet Photoelectron Spectroscopy (UPS); References; 3: Auger Electron Spectroscopy (AES); 3.1 Principles; 3.2 Instrumentation; 3.2.1 Vacuum Requirements; 3.2.2 Electron Sources; 3.2.3 Electron-Energy Analyzers; 3.3 Spectral Information; 3.4 Quantification and Depth Profiling; 3.4.1 Quantification; 3.4.2 Depth Profiling; 3.5 Applications; 3.5.1 Grain

Boundary Segregation; 3.5.2 Semiconductor Technology
3.5.3 Thin Films and Interfaces3.5.4 Surface Segregation; 3.6 Scanning A uger Microscopy (SAM); References; 4: Electron Energy-Loss Spectroscopy (EELS) and Energy-Filtering Transmission Electron Microscopy (EFTEM); 4.1 Principles; 4.2 Instrumentation; 4.3 Qualitative Spectral Information; 4.3.1 Low-Loss Excitations; 4.3.2 Ionization Losses; 4.3.3 Fine Structures; 4.4 Quantification; 4.5 Imaging of Element Distribution; 4.6 Summary; References; 5: Low-Energy Electron Diffraction (LEED); 5.1 Principles and History; 5.2 Instrumentation; 5.3 Qualitative Information; 5.3.1 LEED Pattern
5.3.2 Spot Profile Analysis5.3.3 Applications and Restrictions; 5.4 Quantitative Structural Information; 5.4.1 Principles; 5.4.2 Experimental Techniques; 5.4.3 Computer Programs; 5.4.4 Applications and Restrictions; 5.5 Low-Energy Electron Microscopy; 5.5.1 Principles of Operation; 5.5.2 Applications and Restrictions; References; 6: Other Electron-Detecting Techniques; 6.1 Ion (Excited) Auger Electron Spectroscopy (IAES); 6.2 Ion Neutralization Spectroscopy (INS); 6.3 Inelastic Electron Tunneling Spectroscopy (IETS); Reference; Part Two: Ion Detection
7: Static Secondary Ion Mass Spectrometry (SSIMS)7.1 Principles; 7.2 Instrumentation; 7.2.1 Ion Sources; 7.2.2 Mass Analyzers; 7.2.2.1 Quadrupole Mass Spectrometers; 7.2.2.2 Time-of-Flight Mass Spectrometry (TOF-MS); 7.3 Quantification; 7.4 Spectral Information; 7.5 Applications; 7.5.1 Oxide Films; 7.5.2 Interfaces; 7.5.3 Polymers; 7.5.4 Biosensors; 7.5.5 Surface Reactions; 7.5.6 Imaging; 7.5.7 Ultra-Shallow Depth Profiling; References; 8: Dynamic Secondary Ion Mass Spectrometry (SIMS); 8.1 Principles; 8.1.1 Compensation of Preferential Sputtering; 8.1.2 Atomic Mixing
8.1.3 Implantation of Primary Ions

Sommario/riassunto

Surveying and comparing all techniques relevant for practical applications, this second edition of a bestseller is a vital guide to this hot topic in nano- and surface technology. Completely revised and updated, sections include electron, ion and photon detection, as well as scanning microscopy, while new chapters have been added to cover such recently developed techniques as SNOM, SERS, and laser ablation. Over 500 references and a list of equipment suppliers make this a rapid reference for materials scientists, analytical chemists, and those working in the biotechnological industry.

3. Record Nr. UNINA9910781414203321

Titolo	Heroines of Jiangyong [[electronic resource]] : Chinese narrative ballads in women's script / / translation & introduction by Wilt L. Idema
Pubbl/distr/stampa	Seattle, : University of Washington Press, c2009
ISBN	0-295-80011-9
Descrizione fisica	viii, 181 p. : ill
Classificazione	18.86
Altri autori (Persone)	IdemaW. L (Wilt L.)
Disciplina	895.1/1520809287
Soggetti	Chinese poetry - Women authors Chinese poetry - China - Jiangyong Xian Chinese poetry - 20th century
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Translated from the Chinese.
Nota di bibliografia	Includes bibliographical references (p. 177-181).
Nota di contenuto	Moral tracts. Admonitions for my daughter ; The ten months of pregnancy ; The family heirloom ; The lazy wife -- Narrative ballads. The tale of third sister ; The daughter of the Xiao family ; Lady Luo ; The Maiden Meng Jiang ; The flower seller ; The demonic carp ; The karmic affinity of Liang Shanbo and Zhu Yingtai ; Fifth daughter Wang.